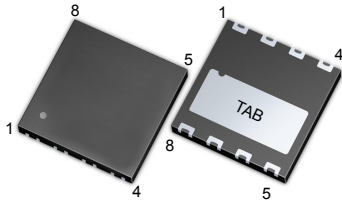
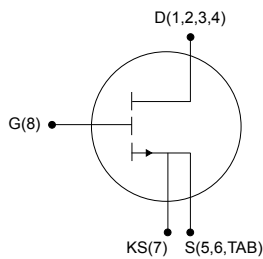


## 700 V, 60 mΩ typ., 29 A, e-mode PowerGaN transistor



DFN 8x8



G8D1234S56TABKS7



### Product status link

[SGT080R70ILB](#)

### Product summary

Order code	SGT080R70ILB
Marking	080R70I
Package	DFN 8x8
Packing	Tape and reel

### Features

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>	Series
SGT080R70ILB	700 V	80 mΩ	29 A	G-HEMT

- Enhancement mode normally off transistor
- Very high switching speed
- High power management capability
- Extremely low capacitances
- Kelvin source pad for optimum gate driving
- Zero reverse recovery charge

### Applications

- Adapters for tablets, notebook and AIO
- USB type-C PD adapters and quick chargers
- AC-DC converters
- DC-DC converters

### Description

The SGT080R70ILB is a 700 V, 29 A e-mode PowerGaN transistor combined with a well established packaging technology. The resulting G-HEMT device provides extremely low conduction losses, high current capability and ultra fast switching operation to enable high power density and unbeatable efficiency performances.

# 1 Electrical ratings

$T_C = 25\text{ °C}$  unless otherwise specified.

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	700 <sup>(1)</sup>	V
	Drain-source voltage (transient, $t_p < 200\ \mu\text{s}$ )	800	
$V_{GS}$	Gate-source voltage	-6 to 7	V
$I_D$	Drain current (continuous)	29 <sup>(2)</sup>	A
$I_{DM}$	Pulse drain current ( $t_p = 10\ \mu\text{s}$ )	58	A
$P_{TOT}$	Total power dissipation at $T_C = 25\text{ °C}$	188 <sup>(2)</sup>	W
$T_{stg}$	Storage temperature range	-55 to 150	°C
$T_J$	Operating junction temperature range		°C

1. Recommended continuous maximum bus voltage during switching operations should not exceed 450 V.
2. Limited by design.

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance, junction-to-case	0.52	°C/W
$R_{thJA}$	Thermal resistance, junction-to-ambient	33.6 <sup>(1)</sup>	°C/W

1. When mounted on a standard 1 inch<sup>2</sup> area of FR-4 PCB with 2-oz copper.

## 2 Electrical characteristics

$T_C = 25\text{ °C}$  unless otherwise specified.

**Table 3. Static**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{DSS}$	Drain-source leakage current	$V_{GS} = 0\text{ V}, V_{DS} = 700\text{ V}$		5	65	$\mu\text{A}$
		$V_{GS} = 0\text{ V}, V_{DS} = 700\text{ V}, T_J = 150\text{ °C}$		13	390 <sup>(1)</sup>	
$I_{GSS}$	Gate-source leakage current	$V_{DS} = 0\text{ V}, V_{GS} = 6\text{ V}$		163		$\mu\text{A}$
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 30.7\text{ mA}$	1.2	1.7	2.5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 6\text{ V}, I_D = 8\text{ A}$		60	80	m $\Omega$
		$V_{GS} = 6\text{ V}, I_D = 8\text{ A}, T_J = 150\text{ °C}$		135		

1. Specified by design, not tested in production.

**Table 4. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{GS} = 0\text{ V}, V_{DS} = 400\text{ V}, f = 100\text{ kHz}$	-	225	-	pF
$C_{oss}$	Output capacitance		-	70	-	pF
$C_{rSS}$	Reverse transfer capacitance		-	0.5	-	pF
$C_{o(er)}^{(1)}$	Equivalent output capacitance energy related	$V_{GS} = 0\text{ V}, V_{DS} = 0\text{ to }400\text{ V}$	-	105	-	pF
$C_{o(tr)}^{(2)}$	Equivalent output capacitance time related		-	150	-	pF
$R_g$	Intrinsic gate resistance	$f = 5\text{ MHz}, I_D = 0\text{ A}$	-	3	-	$\Omega$
$V_{plat}$	Gate plateau voltage	$V_{DS} = 400\text{ V}, I_D = 8\text{ A}$	-	2.2	-	V
$Q_g$	Total gate charge	$V_{GS} = 0\text{ to }6\text{ V}, V_{DS} = 400\text{ V}, I_D = 8\text{ A}$	-	6.2	-	nC
$Q_{gs}$	Gate-source charge		-	0.5	-	nC
$Q_{gd}$	Gate-drain charge		-	2.2	-	nC
$Q_{rr}$	Reverse recovery charge	$V_{GS} = 0\text{ V}, V_{DS} = 400\text{ V}$	-	0	-	nC
$Q_{oss}$	Output charge		-	60	-	nC

1.  $C_{o(er)}$  is a constant capacitance value that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to the stated value.

2.  $C_{o(tr)}$  is a constant capacitance value that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to the stated value.

**Table 5. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DS} = 400\text{ V}, I_D = 16\text{ A}, V_{GS} = 6\text{ V},$ $R_{G(on)} = 10\text{ }\Omega, R_{G(off)} = 2\text{ }\Omega, L = 318\text{ }\mu\text{H}$	-	3	-	ns
$t_r$	Rise time		-	4	-	ns
$t_{d(off)}$	Turn-off delay time		-	5	-	ns
$t_f$	Fall time		-	4	-	ns

**Table 6. Reverse conduction**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{SD}$	Source-drain reverse voltage	$V_{GS} = 0\text{ V}$ , $I_{SD} = 8\text{ A}$	-	2.3	-	V

## Revision history

Table 7. Document revision history

Date	Revision	Changes
02-Apr-2025	1	First release.

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